Green Journals

International Approved Journals

Journal Information

Journal Title	Microelectronics International
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E-ISSN	1758-812X
Database	SCOPUS
Domain	Health Sciences, Physical Sciences, Social Sciences

Classification History

Year	A+	A	B	C
2026		✓	✓	
2025		✓	✓	
2024		✓	✓	
2023		✓	✓	
2021/2022		✓	✓	
2020		✓	✓	
2019		✓	✓	
2018		✓		

Classification: The table above shows all journal classifications recorded for each classification year in the Green Journals database. A journal may have more than one classification in the same year.

Recent Articles

Reliability analysis of PBGA lead-free interconnect solder joints under drop impact load
2026-11-10 Pages 1-13
Authors: Xuexia Yang, Yanxi Sun, Miao Zhu et al.
DOI: 10.1108/mi-02-2026-0033

An advanced control strategy for matrix converters in unbalanced grid voltage conditions
2026-11-3 Pages 1-16
Authors: Sarat Kumar Das, Jayakrushana Moharana, Prasid Syam
DOI: 10.1108/mi-06-2026-0161

Bounded finite-step voltage control of dual-active-bridge converters with constrained triple-phase-shift modulation
2026-10-29 Pages 1-13
Authors: Jun You, Bingxin Xu, Lei Li et al.
DOI: 10.1108/mi-06-2026-0139

Editorial: Opinion: the next infrastructure waves behind AI data centers
2026-10-19 Vol. 43 Issue 4 Pages 213-213
Authors: Chong Leong Gan
DOI: 10.1108/mi-10-2026-310

A wide-input 7–40 V low-dropout regulator and bandgap-referenced precision output
2026-10-14 Pages 1-11
Authors: Ching Chun Hsu, San-Fu Wang, Chi Chun Chen
DOI: 10.1108/mi-03-2026-0053

A narrowband bandpass filter with multiple transmission zeros based on parallel coupled lines structure
2026-9-28 Pages 1-11
Authors: Yanhao Liu, Yanxi Pan, Jing Feng et al.
DOI: 10.1108/mi-05-2026-0135

Energy management control of grid-tied PV-battery system based on intelligent proportional allocation
2026-9-21 Pages 1-14
Authors: Jinqi Du, Peng Ye, Hejiang Qian et al.
DOI: 10.1108/mi-02-2026-0024

Room-temperature deposited Ti/Au films on Si toward wafer-level MEMS hermetic packaging
2026-9-15 Vol. 43 Issue 4 Pages 236-245
Authors: Xin Yang, Hao-Feng Chen, Junyuan Zhao et al.
DOI: 10.1108/mi-02-2026-0028

Statistical variability and performance trade-offs induced by 3D line edge roughness in 12-nm 3-stacked nanosheet FETs
2026-9-15 Pages 1-10
Authors: Shekhar Yadav
DOI: 10.1108/mi-06-2026-0144

Design of high-precision, low-power energy metering integrated circuits based on TDM architecture
2026-9-14 Pages 1-11
Authors: Zuohan Zhang
DOI: 10.1108/mi-07-2026-0181